What is claimed is:

1. A method for measuring thickness of an optical disc by using an interference effect of the optical disc layer, comprising the steps of:

5   detecting an intensity of a reflective light according to a wavelength of a light as spectrum data for each wavelength;

converting the detected spectrum data for each wavelength into a spectrum value as a function of a wavelength that a refractive index is reflected; and

10   detecting a position where the intensity of the reflective light has a peak as a thickness of a spacer layer and a cover layer respectively by converting the converted value into a length of an interference area for representing a layer thickness of the optical disc by the Fast Fourier Transform.

15

2. The method of claim 1, wherein the spectrum value as a function of a wavelength that a refractive index is reflected is $n(\lambda)/2\lambda$.

20   3. The method of claim 1, wherein the optical disc layer comprises the spacer layer with a refractive index n_1 and the cover layer with a refractive index n_2 different from the refractive index n1, and respective positions d_1 and d_2 where the intensity of the light obtained by reflecting the refractive

19

index into a function of a wavelength become a peak value are
obtained as the thickness.